

<b>Notice of References Cited</b>	Application/Control No. 09/642,596	Applicant(s)/Patent Under Reexamination DANIELSON, J. D. SHELDON	
	Examiner Richard Hanig	Art Unit 2873	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5757013	05-1998	Groger et al	250/458.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<del>*</del>	U	Vadde et al, A closed loop scheme for phase-sensitive fluorometry, Rev. Sci. Instrum. 66 (7), July 1995, p.3750.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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